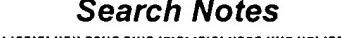


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/698,132	YIP, CHIFAI
	Examiner	Art Unit
	Sanh D. Phu	2618

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner